APPARATUS AND METHODS FOR MEASURING REACTION BYPRODUCTS
Inventors: Andy C. Neilson et al.
Attorney: James R. Abney
Telephone: (503) 224-6655
Our File – FSII 308

Fig. 1

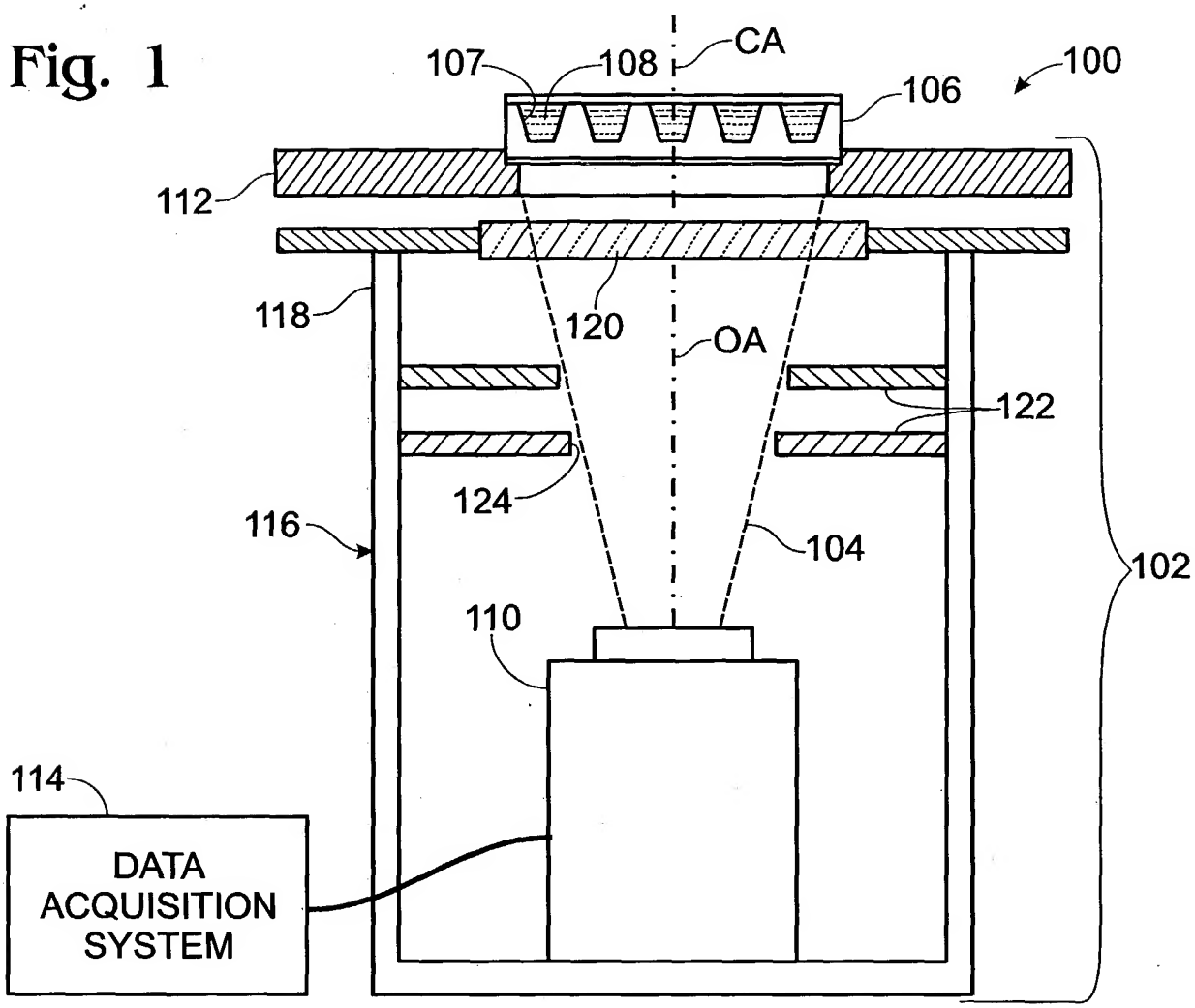


Fig. 2

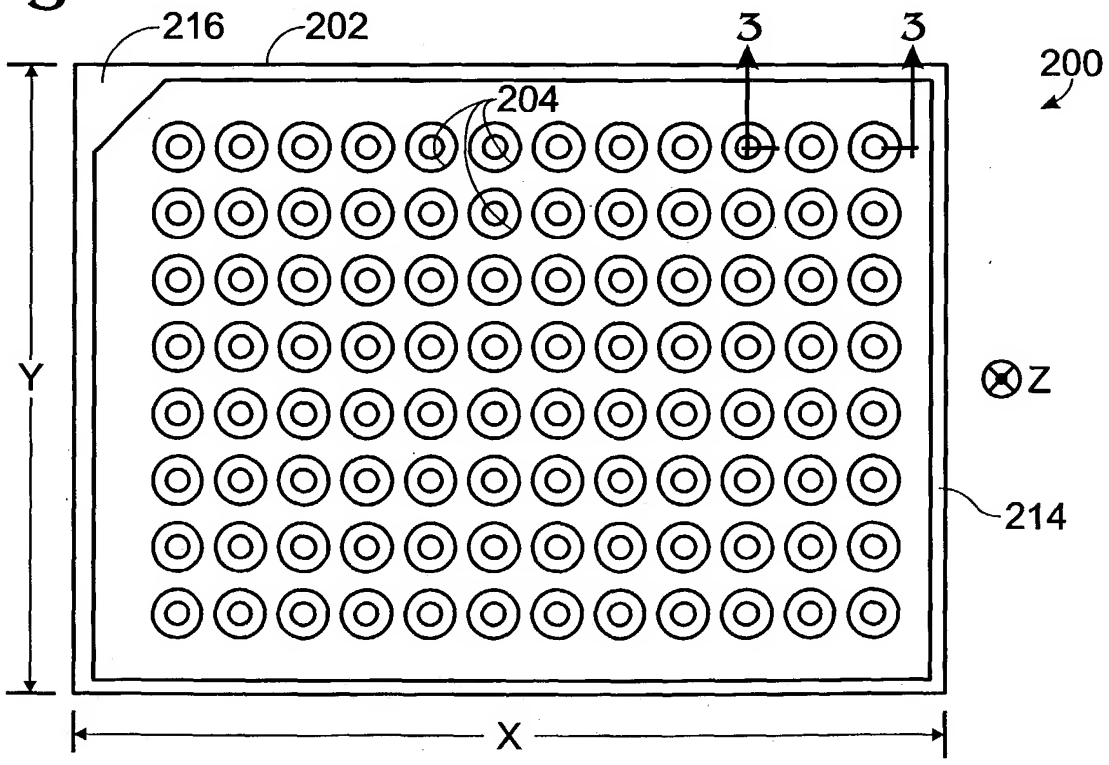


Fig. 3

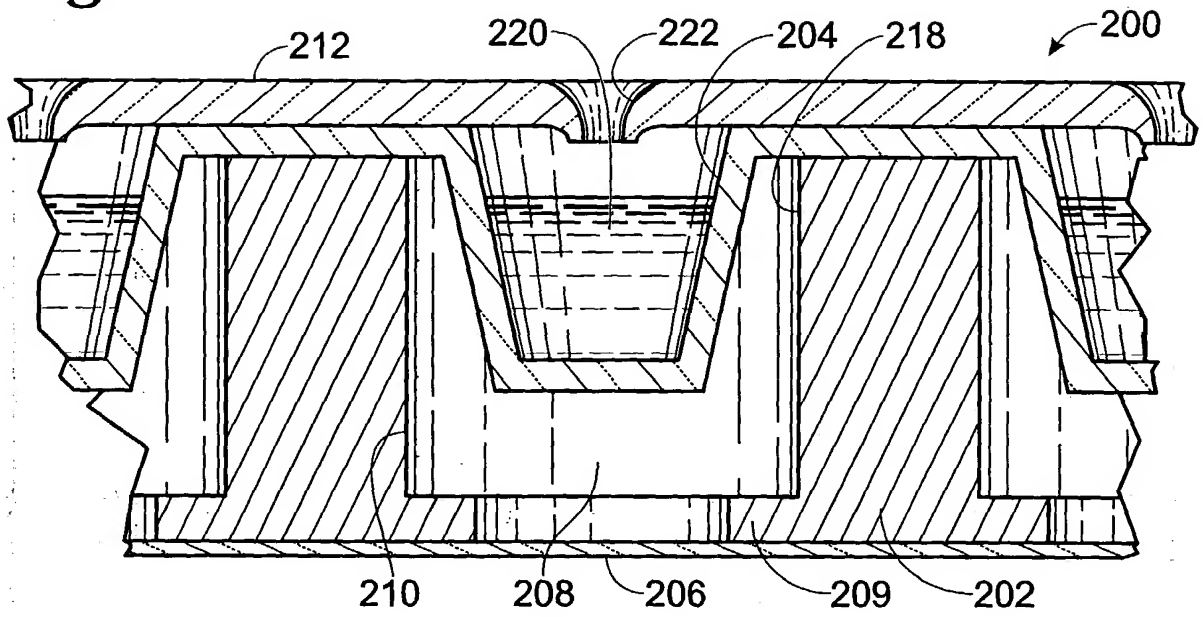

212
220
222
204
218
200
210
208
206
209
202

Fig. 4

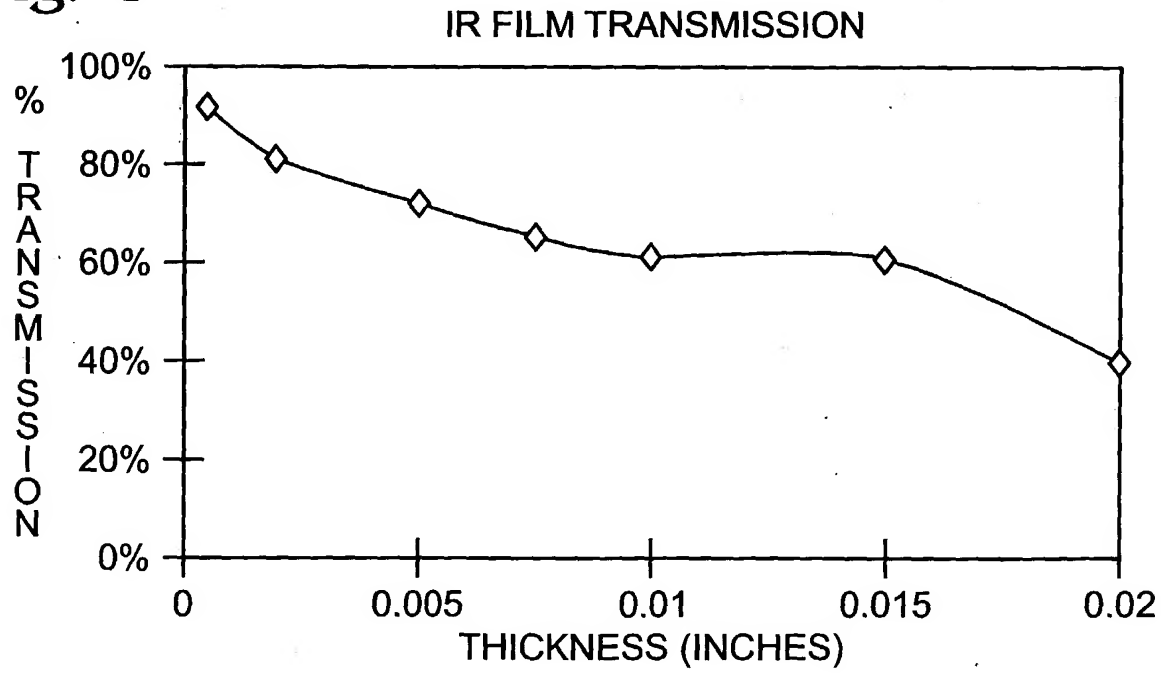
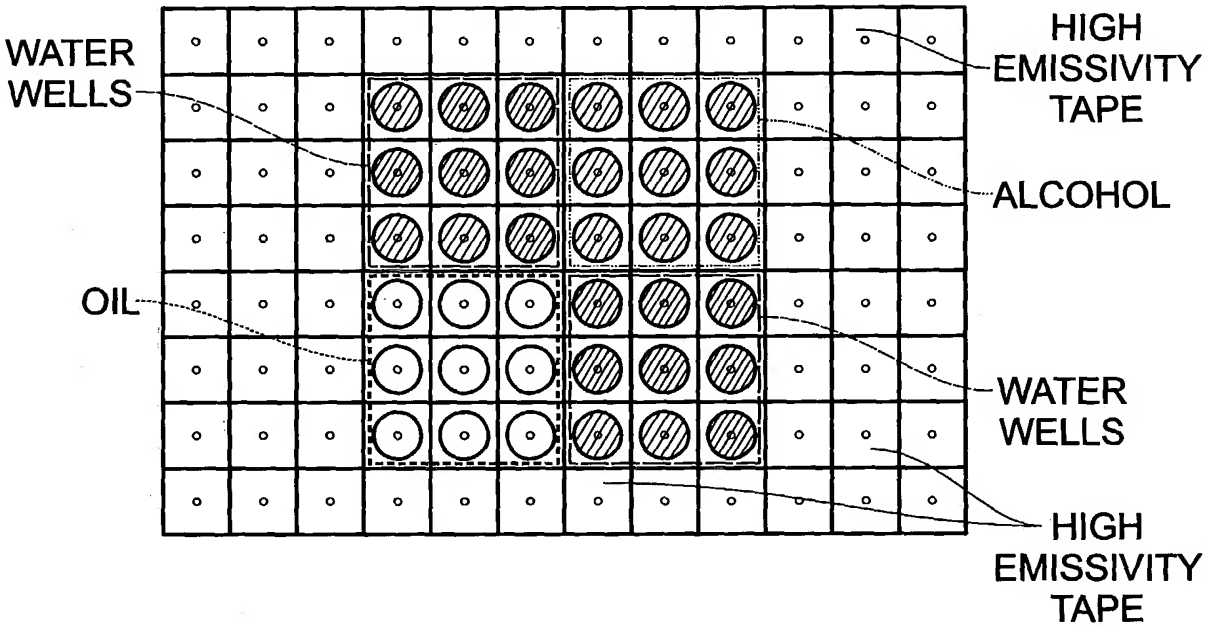

IR FILM TRANSMISSION
% TRANSMISSION
100%
80%
60%
40%
20%
0%
0
0.005
0.01
0.015
0.02
THICKNESS (INCHES)

Fig. 5

FABRICATED PER DESIGN CONSTRUCTION



STANDARD 96 WELL MICROPLATE
(COSTAR 3628) "POLYSTYRENE"

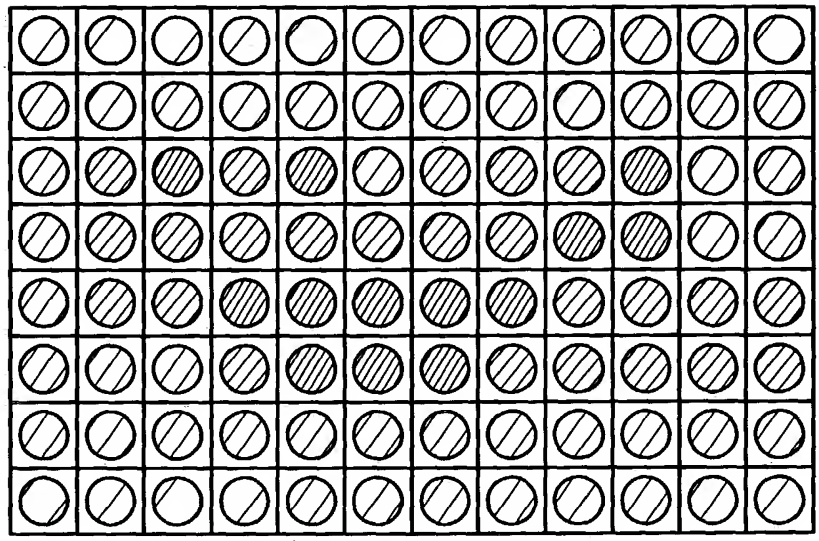


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Fig. 6

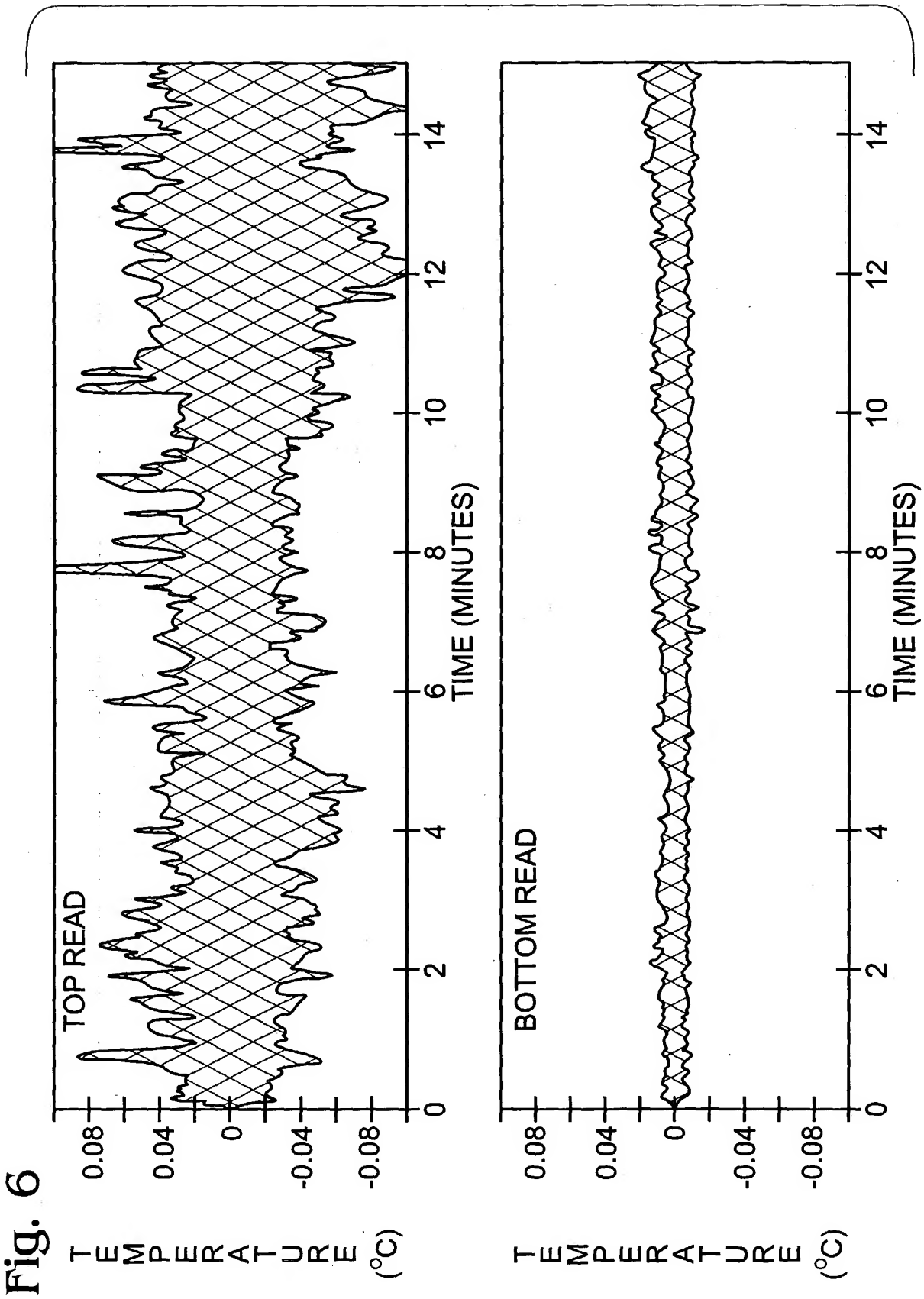

Fig. 7

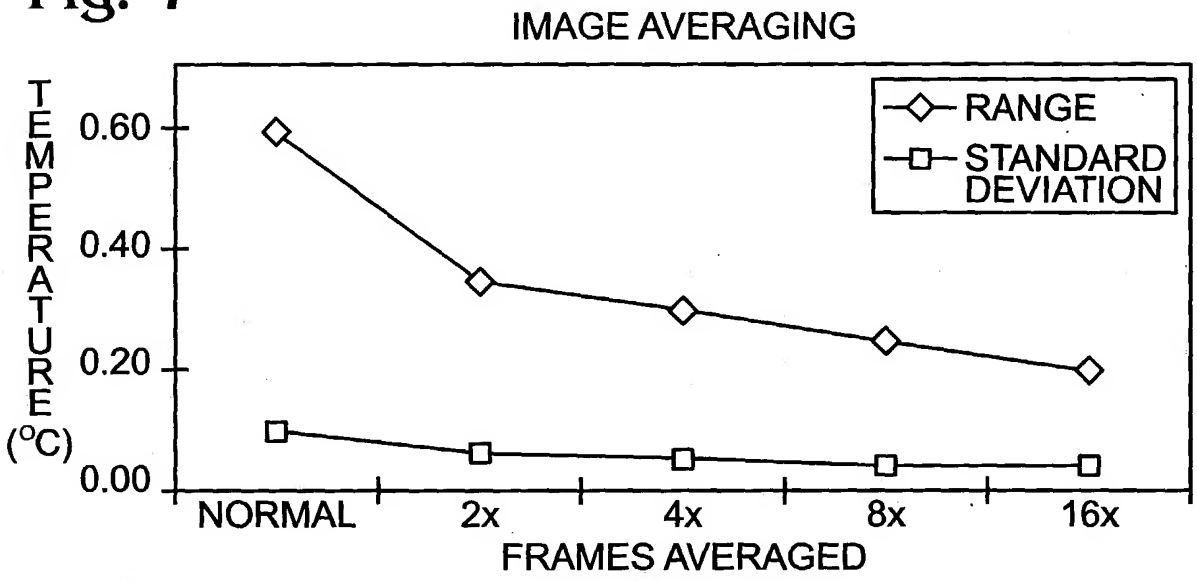
IMAGE AVERAGING
TEMPERATURE (°C)
0.60
0.40
0.20
0.00
RANGE
STANDARD DEVIATION
NORMAL
2x
4x
8x
16x
FRAMES AVERAGED

Fig. 8

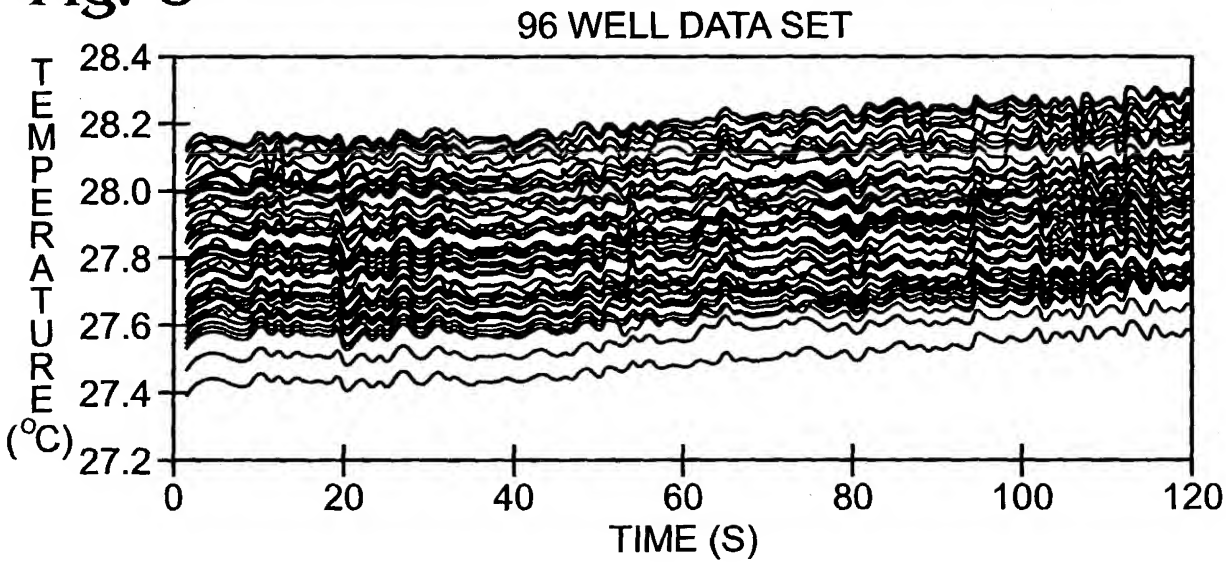
96 WELL DATA SET
TEMPERATURE (°C)
28.4
28.2
28.0
27.8
27.6
27.4
27.2
0
20
40
60
80
100
120
TIME (S)

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Fig. 9

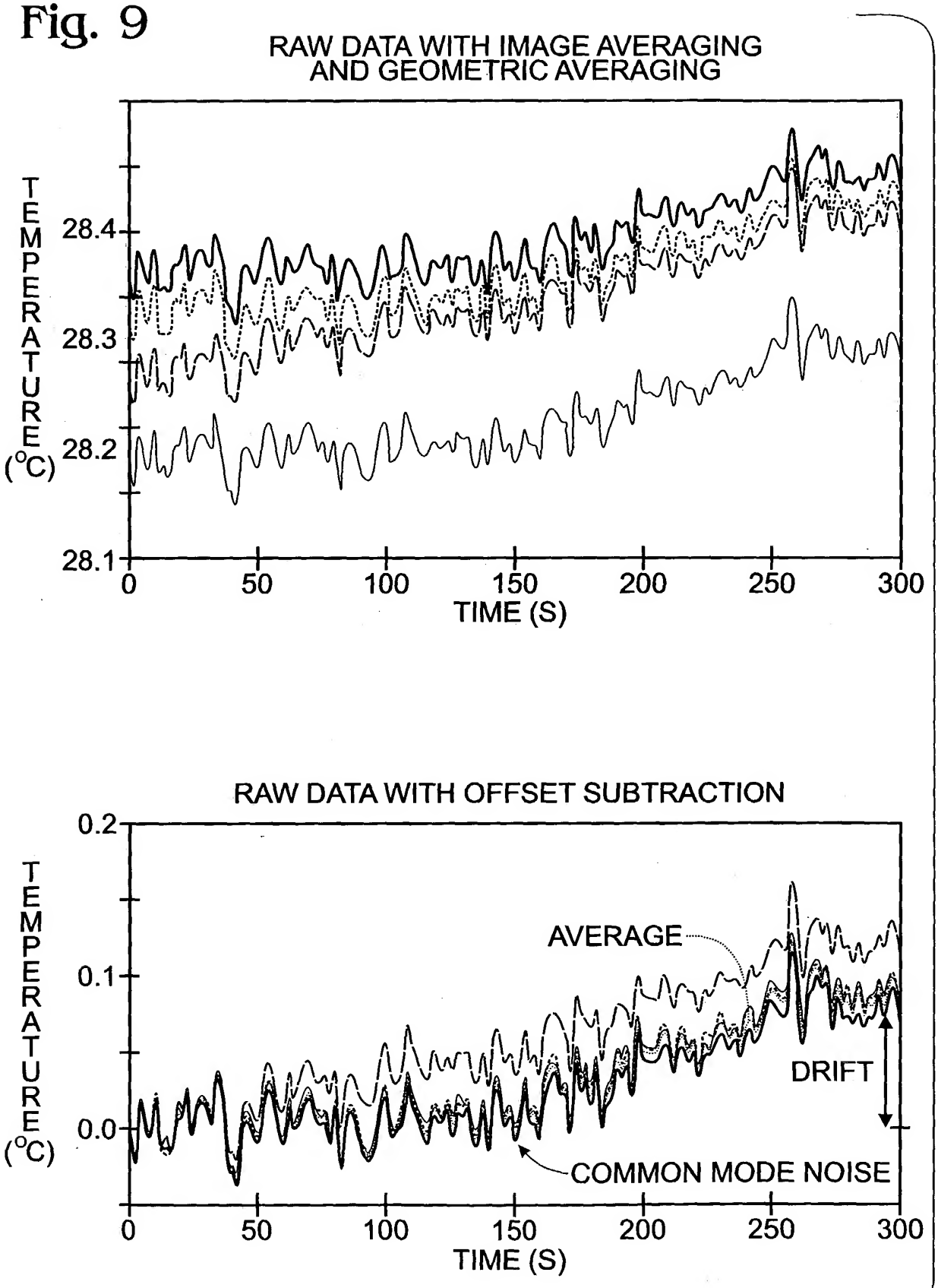

Fig. 10

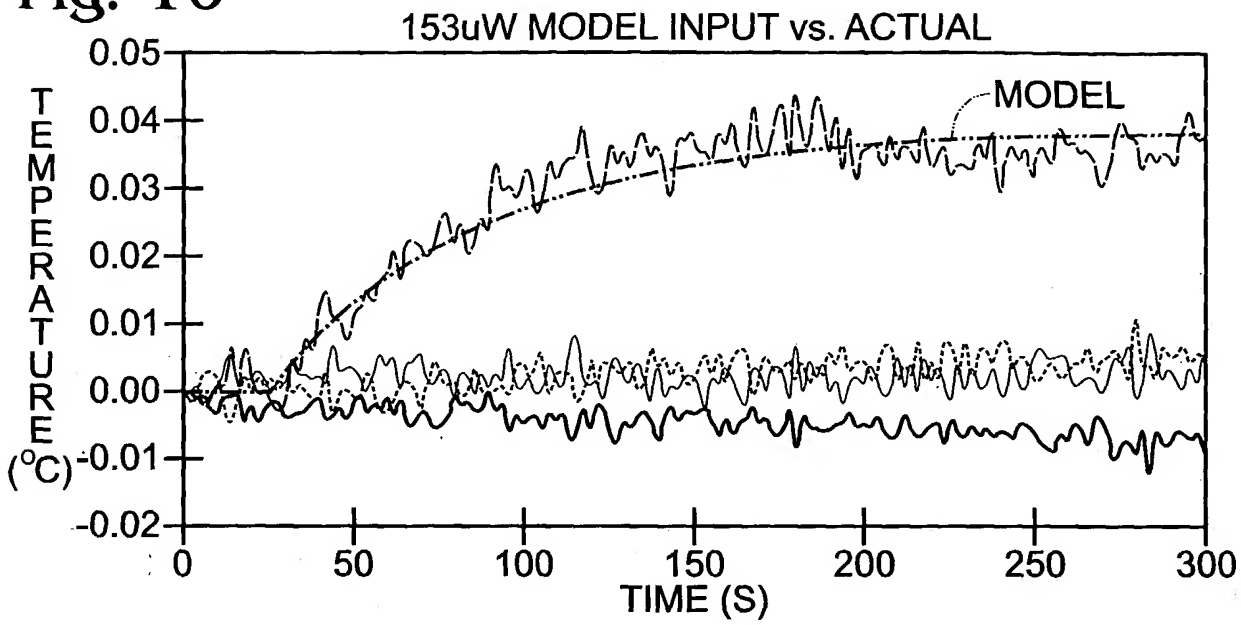
153uW MODEL INPUT vs. ACTUAL
MODEL
TEMPERATURE (°C)
0.05
0.04
0.03
0.02
0.01
0.00
-0.01
-0.02
0
50
100
150
200
250
300
TIME (S)

Fig. 11

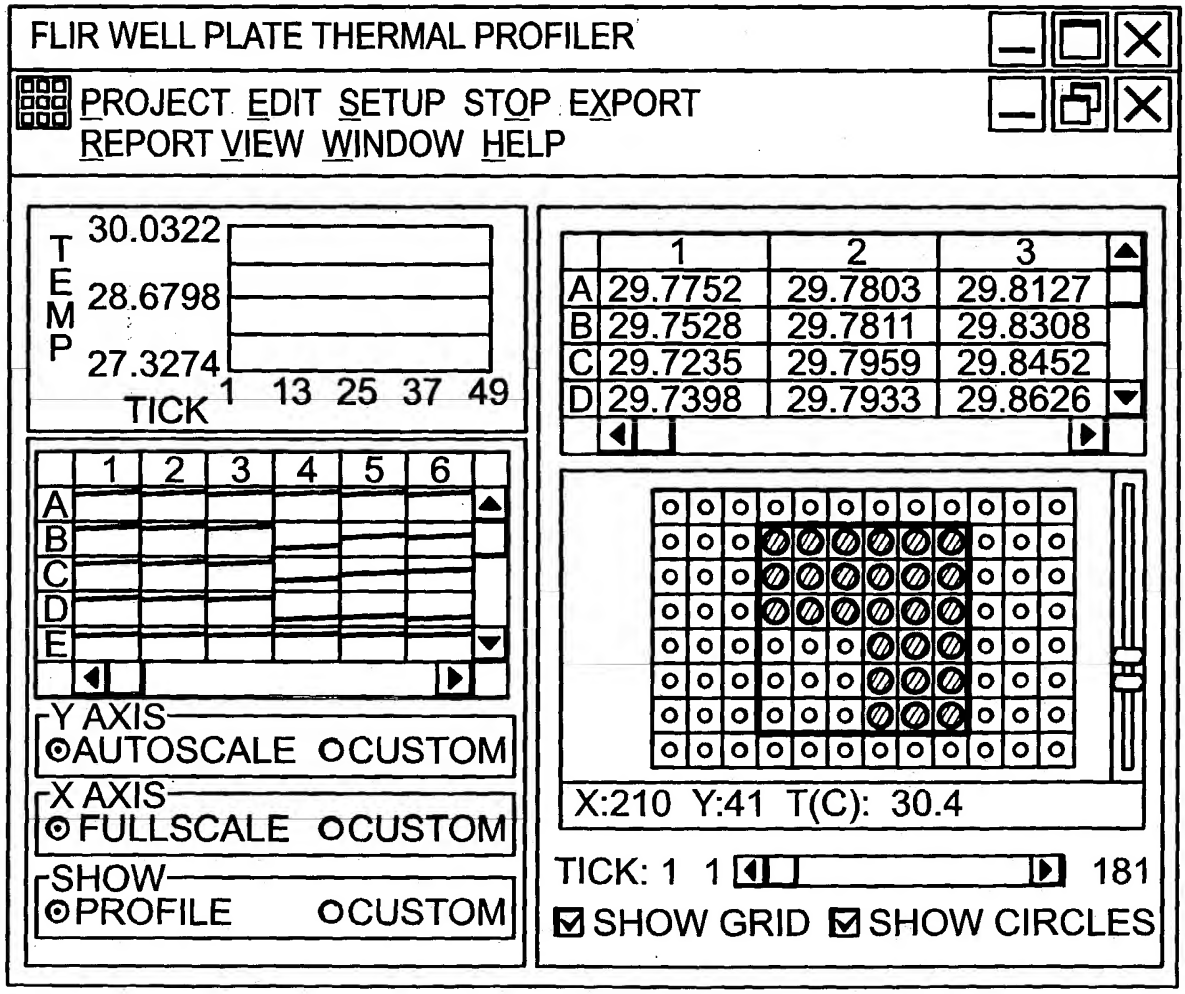
FLIR WELL PLATE THERMAL PROFILER
PROJECT EDIT SETUP STOP EXPORT
REPORT VIEW WINDOW HELP
TEMP
30.0322
28.6798
27.3274
TICK 1 13 25 37 49
1 2 3
A 29.7752 29.7803 29.8127
B 29.7528 29.7811 29.8308
C 29.7235 29.7959 29.8452
D 29.7398 29.7933 29.8626
1 2 3 4 5 6
A
B
C
D
E
Y AXIS
AUTOSCALE CUSTOM
X AXIS
FULLSCALE CUSTOM
SHOW
PROFILE CUSTOM
X:210 Y:41 T(C): 30.4
TICK: 1 1 181
SHOW GRID SHOW CIRCLES

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Fig. 12

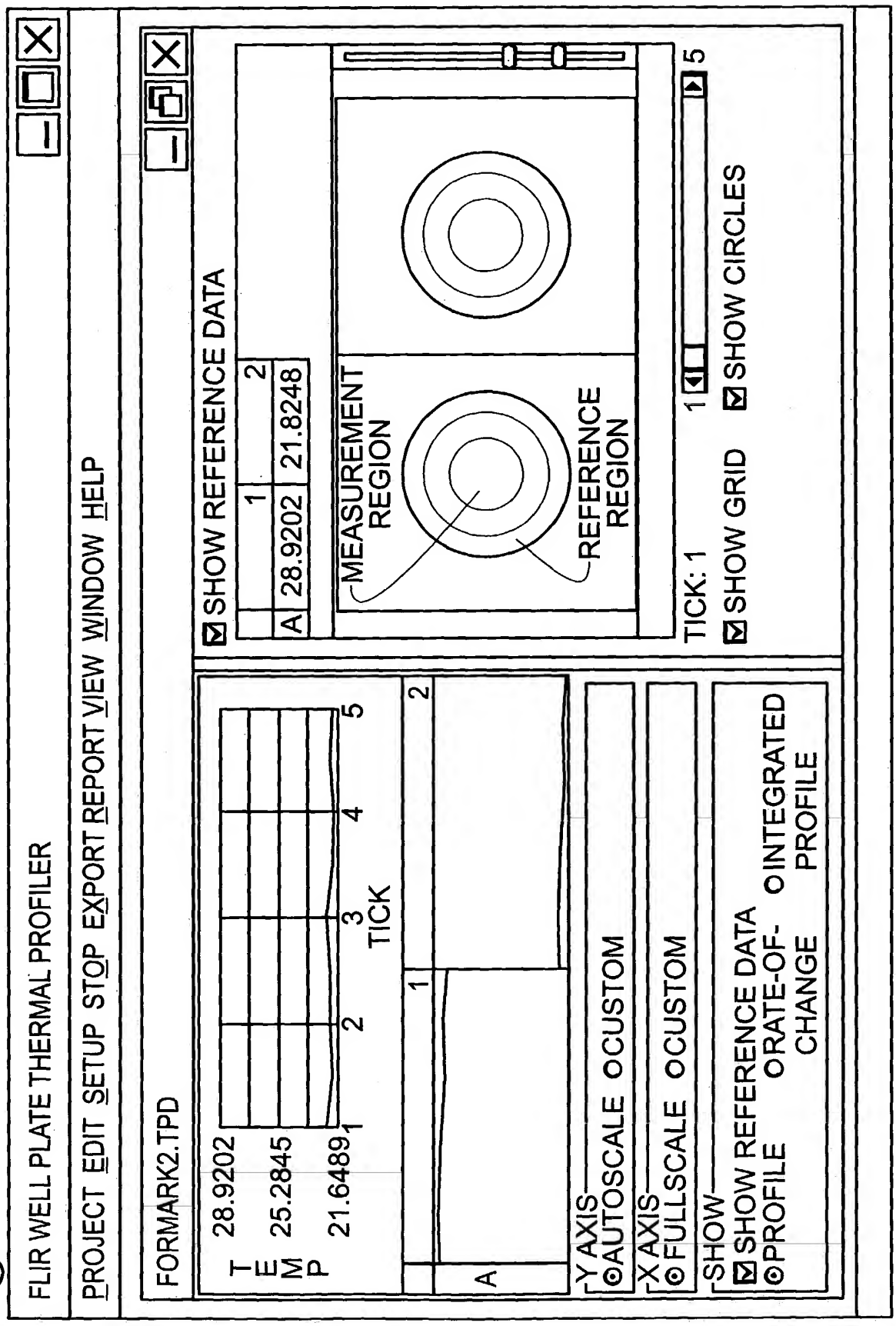

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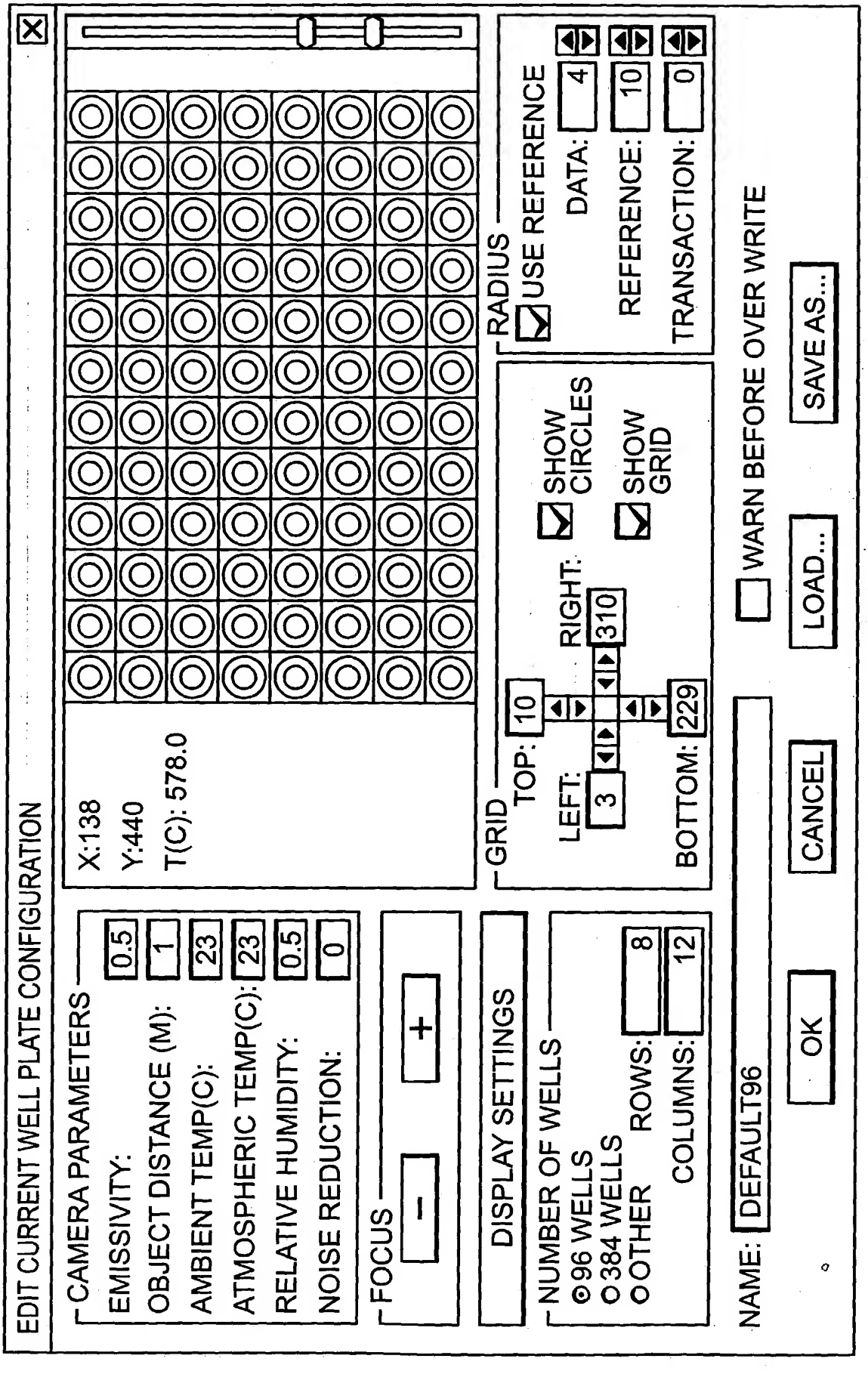
Fig. 13



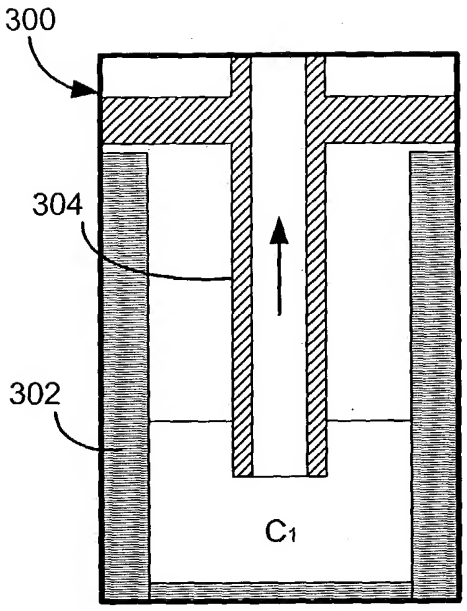


Fig. 14A

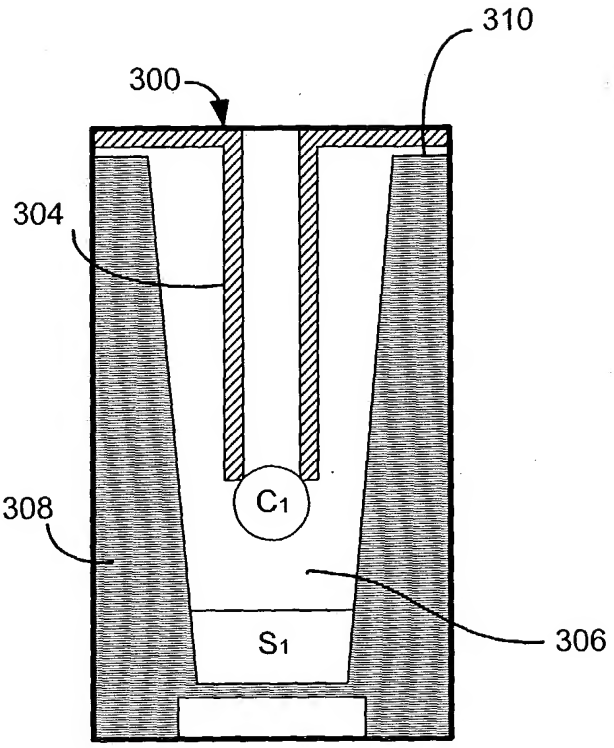


Fig. 14B

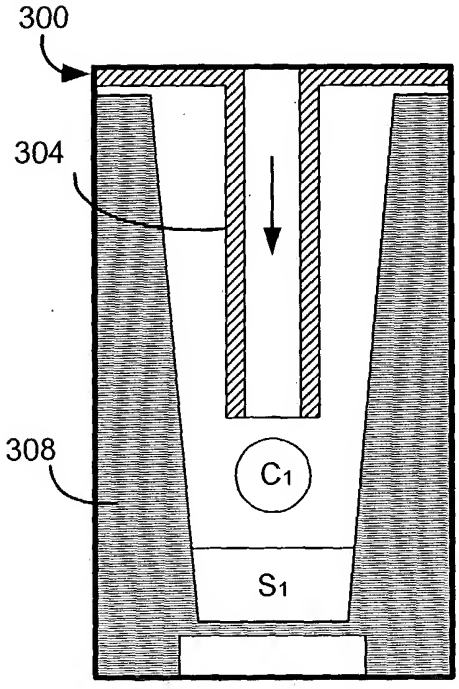


Fig. 14C

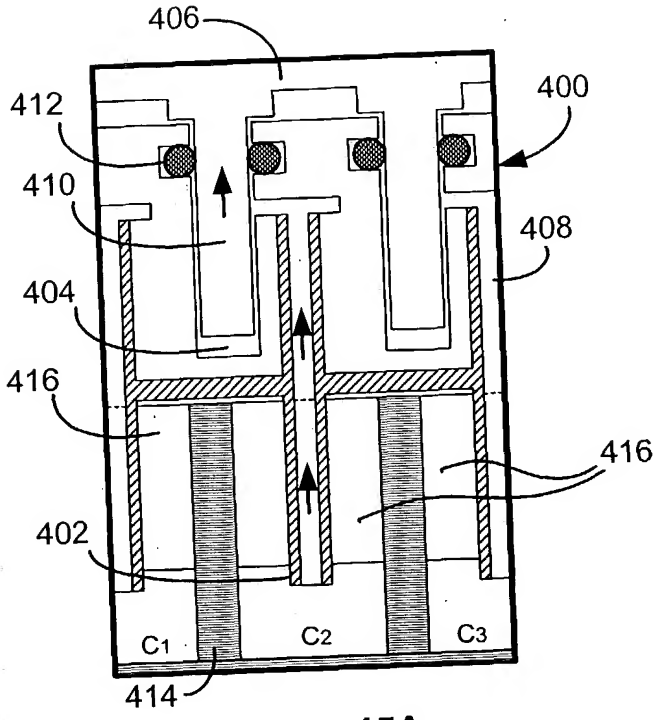


Fig. 15A

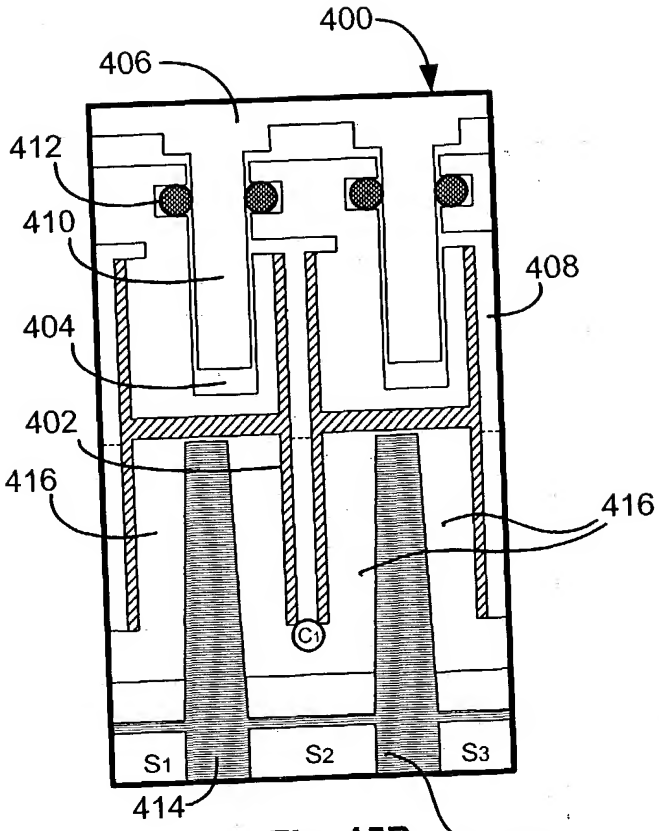


Fig. 15B

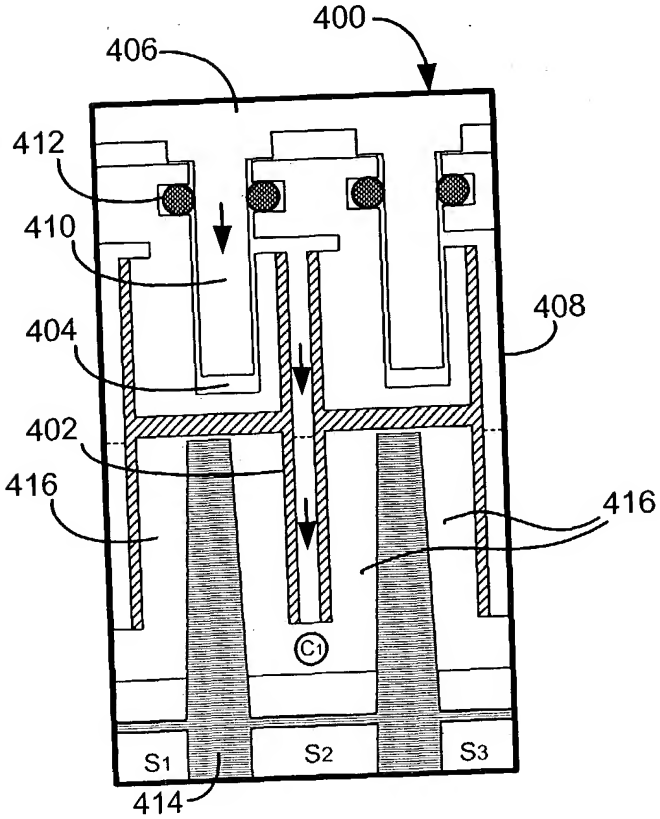


Fig. 15C

Fig. 16

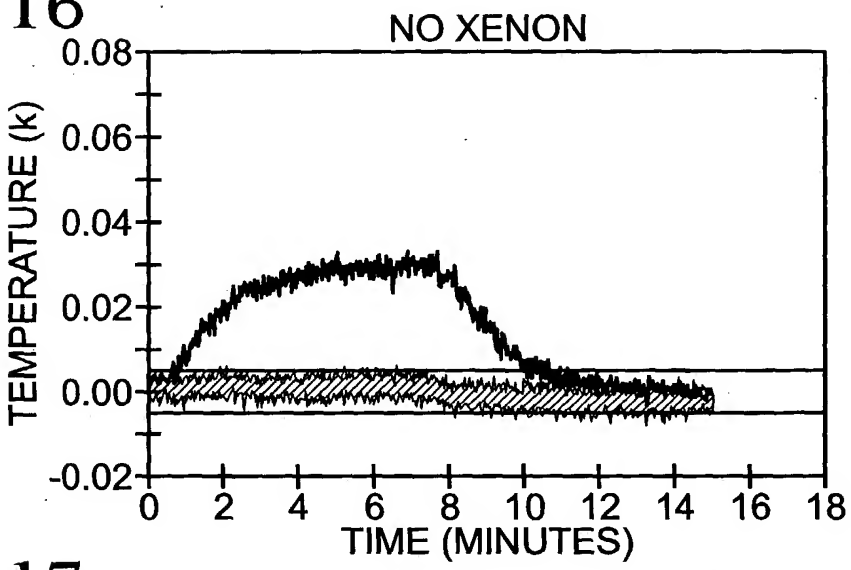


Fig. 17

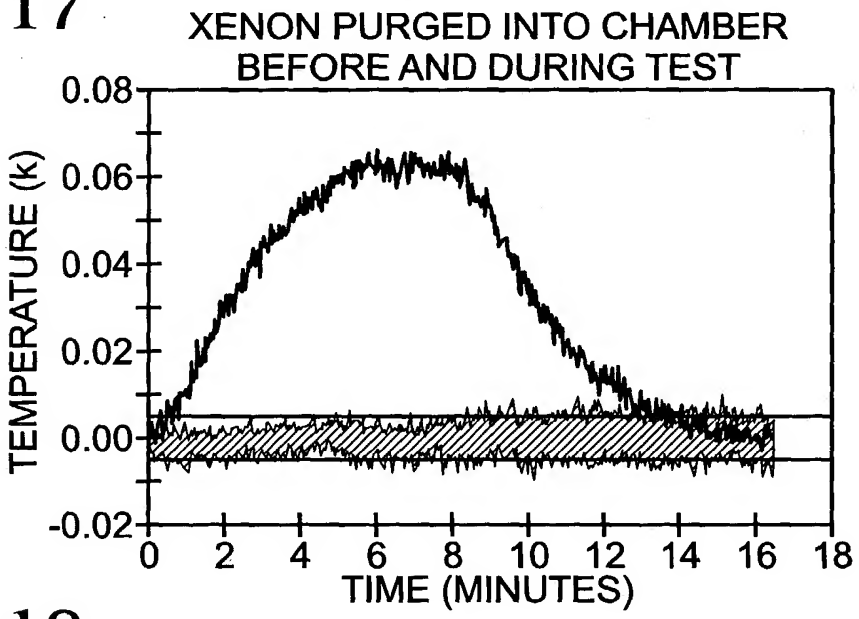
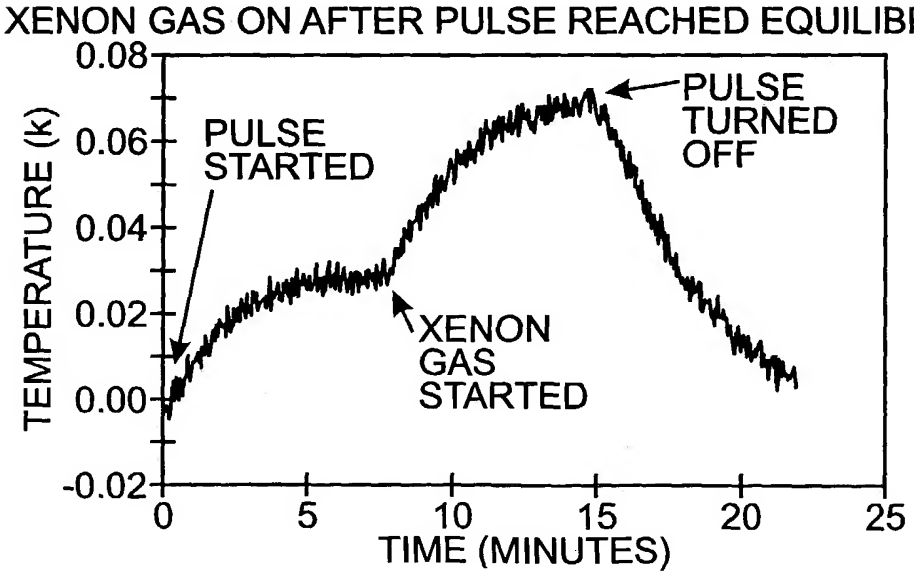



Fig. 18